

## CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the application:

1-8. (Canceled)

9. (Currently Amended) A method for testing an integrated device comprising:

\_\_\_\_\_strobing a data with a strobe edge; and measuring a setup parameter for at least one input/output circuit by pulling in the strobe edge in predetermined decrements up to a single phase of a clock, inverting the clock after the strobe edge has been pulled in by at least the single phase of the clock; and  
\_\_\_\_\_holding the strobe edge constant, after the strobe edge has been pulled in by at least the single phase of the clock, while pushing the data out in predetermined increments.

10. (Currently Amended) The method of claim 9 measuring the setup parameter comprises providing data from a functional logic block ([|or|] FLB) within the integrated device.

11. (Original) The method of claim 10 wherein providing data comprises driving the data out through an output component of at least one input/output circuit.

12. (Original) The method of claim 9 wherein the strobe edge is on a falling edge of the clock and the data is on the rising edge of the clock.

13. (Original) The method of claim 9 wherein pushing the data comprises pushing out a rising edge of the inverted clock.

14. (Currently Amended) A method for testing an integrated device comprising:

\_\_\_\_\_strobing a data with a strobe edge; [[and]]

\_\_\_\_\_measuring a hold parameter for at least one input/output circuit by pulling in the strobe edge in predetermined decrements up to a single phase of a clock, inverting the clock after the strobe edge has been pulled in by at least the single phase of the clock; and

\_\_\_\_\_holding the strobe edge constant, after the strobe edge has been pulled in by at least the single phase of the clock, while pushing the data out in predetermined increments.

15. (Currently Amended) The method of claim 14 measuring the hold parameter comprises providing data from a functional logic block ([[or]] FLB) within the integrated device.

16. (Original) The method of claim 15 wherein providing data comprises driving the data out through an output component of at least one input/output circuit.

17. (Original) The method of claim 14 wherein the strobe edge is on a falling edge of the clock and the data is on the rising edge of the clock.

18. (Original) The method of claim 14 wherein pushing the data comprises pushing out a rising edge of the inverted clock.

19-24. (Cancelled)

25. (Currently Amended) An apparatus comprising:  
\_\_\_\_\_ a plurality of input/output circuit to be tested by [[an]] a central control [[10]]  
loopback test that: strobes a data with a strobe edge; and  
\_\_\_\_\_ measures a setup parameter for at least one input/output circuit by pulling in the  
strobe edge in predetermined decrements up to a single phase of a clock;  
\_\_\_\_\_ the apparatus to invert the clock after the strobe edge has been pulled in by at least  
the single phase of the clock; and hold the strobe edge constant, after the strobe edge has  
been pulled in by at least the single phase of the clock, while pushing the data out in  
predetermined increments.

26. (Canceled)

27. (Currently Amended) The apparatus of claim 25 [[26]] wherein the apparatus is a processor.